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	CORR	E07	ren	Application Number	10/542316		
	CORR			Filing Date	July 13, 2005		
1	NFORMATION			First Named Inventor	Hiromasa Tanobe		
S	TATEMENT E	3Y /	APPLICANT	Art Unit	N/A 2613		
L	(Use as many sheets as necessary)			Examiner Name	Not Yet Assigned D. Singh		
Sheet	1	of	3	Attorney Docket Number	5259-000054/US/NP		

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Examiner Initials*	Cite No.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear) , ,
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NON PATENT LITERATURE DOCUMENTS						
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²			
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Examiner Signature	/Dalzid Singh/	(06/27/2006)	Date Considered